

Most Frequently Occurring Classifications of Patents Returned
From A Search of 10822193 on March 13, 2006

Original Classifications

3 324/158.1
3 430/30
3 438/14
2 174/68.1
2 257/48
2 324/763
2 324/765
2 326/16
2 360/137
2 430/5

Cross-Reference Classifications

3 324/765
3 438/18
2 74/483PB
2 204/192.15
2 250/491.1
2 250/559.37
2 250/559.38
2 257/48
2 257/E21.314
2 257/E23.145
2 326/39
2 326/44
2 355/53
2 356/401
2 358/406
2 360/69
2 360/74.1
2 377/129
2 377/72
2 430/22
2 438/622
2 700/121
2 714/725
2 716/4

Combined Classifications

5 324/765
4 257/48
4 324/158.1
4 430/30
4 438/14
3 324/763
3 355/53
3 358/406
3 430/5
3 438/18
2 73/45.4
2 74/483PB
2 174/68.1
2 204/192.15
2 250/491.1
2 250/559.37
2 250/559.38
2 257/758
2 257/797
2 257/E21.314

10822193_CLS.txt

2 257/E23.145
2 324/537
2 324/72.5
2 324/751
2 326/16
2 326/39
2 326/44
2 356/401
2 356/614
2 360/137
2 360/69
2 360/74.1
2 377/129
2 377/72
2 399/16
2 430/22
2 438/11
2 438/622
2 700/121
2 714/725
2 716/4

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10822193 on March 13, 2006

- 5 324/765 (2 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/765 ..Test of semiconductor device
- 4 257/48 (2 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/48 TEST OR CALIBRATION STRUCTURE
- 4 324/158.1 (3 OR, 1 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/158.1 MISCELLANEOUS
- 4 430/30 (3 OR, 1 XR)
Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
COMPOSITION, OR PRODUCT THEREOF
430/30 INCLUDING CONTROL FEATURE RESPONSIVE TO A TEST
OR MEASUREMENT
- 4 438/14 (3 OR, 1 XR)
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/14 WITH MEASURING OR TESTING
- 3 324/763 (2 OR, 1 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/763 ..DUT including test circuit
- 3 355/53 (1 OR, 2 XR)
Class 355 : PHOTOCOPYING
355/18 PROJECTION PRINTING AND COPYING CAMERAS
355/53 .Step and repeat
- 3 358/406 (1 OR, 2 XR)
Class 358 : FACSIMILE AND STATIC PRESENTATION PROCESSING
358/400 FACSIMILE
358/406 .Facsimile measuring, testing, or calibrating
- 3 430/5 (2 OR, 1 XR)
Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
COMPOSITION, OR PRODUCT THEREOF
430/4 RADIATION MODIFYING PRODUCT OR PROCESS OF
MAKING
430/5 .Radiation mask
- 3 438/18 (0 OR, 3 XR)
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/14 WITH MEASURING OR TESTING
438/17 .Electrical characteristic sensed
438/18 ..Utilizing integral test element

- 2 73/45.4 (1 OR, 1 XR)
 Class 073 : MEASURING AND TESTING
 73/37 WITH FLUID PRESSURE
 73/40 .Leakage
 73/41 ..Conveyor feed
 73/45 ...With defective article discard
 73/45.1Automatic
 73/45.4Sealed receptacle
- 2 74/483PB (0 OR, 2 XR)
 Class 074 : MACHINE ELEMENT OR MECHANISM
 74/469 CONTROL LEVER AND LINKAGE SYSTEMS
 74/479.01 .Multiple controlling elements for single
 controlled element
 74/483R ..Interlocked
 74/483PB ...Push button
- 2 174/68.1 (2 OR, 0 XR)
 Class 174 : ELECTRICITY: CONDUCTORS AND INSULATORS
 174/68.1 CONDUITS, CABLES OR CONDUCTORS
- 2 204/192.15 (0 OR, 2 XR)
 Class 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY
 204/192.1 .Coating, forming or etching by sputtering
 204/192.12 ..Glow discharge sputter deposition (e.g.,
 cathode sputtering, etc.)
 204/192.15 ...Specified deposition material or use
- 2 250/491.1 (0 OR, 2 XR)
 Class 250 : RADIANT ENERGY
 250/491.1 MEANS TO ALIGN OR POSITION AN OBJECT RELATIVE
 TO A SOURCE OR DETECTOR
- 2 250/559.37 (0 OR, 2 XR)
 Class 250 : RADIANT ENERGY
 250/200 PHOTOCELLS; CIRCUITS AND APPARATUS
 250/559.01 .With circuit for evaluating a web, strand,
 strip, or sheet
 250/559.29 ..Measuring position
 250/559.37 ...Angular orientation (e.g., skew)
- 2 250/559.38 (0 OR, 2 XR)
 Class 250 : RADIANT ENERGY
 250/200 PHOTOCELLS; CIRCUITS AND APPARATUS
 250/559.01 .With circuit for evaluating a web, strand,
 strip, or sheet
 250/559.29 ..Measuring position
 250/559.38 ...Determining range from detector
- 2 257/758 (1 OR, 1 XR)
 Class 257 : ACTIVE SOLID-STATE DEVICES
 257/734 COMBINED WITH ELECTRICAL CONTACT OR LEAD
 257/741 .Of specified material other than unalloyed
 aluminum
 257/750 ..Layered
 257/758 ...Multiple metal levels on semiconductor,
 separated by insulating layer (e.g., multiple level
 metallization for integrated circuit)
- 2 257/797 (1 OR, 1 XR)
 Class 257 : ACTIVE SOLID-STATE DEVICES
 257/797 ALIGNMENT MARKS

- 2 257/E21.314 (0 OR, 2 XR)
 Class 257 : ACTIVE SOLID-STATE DEVICES
 257/E21.001 PROCESSES OR APPARATUS ADAPTED FOR MANUFACTURE
 OR TREATMENT OF SEMICONDUCTOR OR SOLID-STATE
 DEVICES OR OF
 PARTS THEREOF (EPO)
 257/E21.002 .Manufacture or treatment of semiconductor
 device (EPO)
 257/E21.04 ..Device having at least one potential-jump
 depletion barrier or surface barrier, e.g., PN junction,
 layer, carrier concentration layer (EPO)
 257/E21.085 ...Device having semiconductor body comprising
 without Group IV elements or Group III-V compounds with or
 impurities, e.g., doping materials (EPO)
 257/E21.211Treatment of semiconductor body using
 material on process other than deposition of semiconductor
 material, or a substrate, diffusion or alloying of impurity
 257/E21.214To change their surface-physical
 cutting characteristics or shape, e.g., etching, polishing,
 (EPO)
 257/E21.294Deposition/post-treatment of
 layers on noninsulating, e.g., conductive - or resistive -
 insulating layers (EPO)
 257/E21.3Post treatment (EPO)
 257/E21.305Physical or chemical etching of layer,
 e.g., to produce a patterned layer from pre-deposited
 extensive layer (EPO)
 257/E21.314Using mask (EPO)
- 2 257/E23.145 (0 OR, 2 XR)
 Class 257 : ACTIVE SOLID-STATE DEVICES
 257/E23.139 ...Liquid at normal operating temperature of
 device (EPO)
 257/E23.141 .Arrangements for conducting electric current
 another, within device in operation from one component to
 interconnections, e.g., wires, lead frames (EPO)
 257/E23.142 ..Including external interconnections
 body consisting of multilayer structure of conductive and
 insulating layers inseparably formed on semiconductor
 (EPO)
 257/E23.145 ...Via connections in multilevel
 interconnection structure (EPO)
- 2 324/537 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
- 2 324/72.5 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/72 TESTING POTENTIAL IN SPECIFIC ENVIRONMENT
 (E.G., LIGHTNING STROKE)
 324/72.5 .Voltage probe

- 2 324/751 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/750 ..System sensing fields adjacent device under
 test (DUT)
 324/751 ...Using electron beam probe
- 2 326/16 (2 OR, 0 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/16 WITH TEST FACILITATING FEATURE
- 2 326/39 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
 UNIVERSAL, ETC.)
 326/39 .Array (e.g., PLA, PAL, PLD, etc.)
- 2 326/44 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
 UNIVERSAL, ETC.)
 326/39 .Array (e.g., PLA, PAL, PLD, etc.)
 326/44 ..Field effect transistor
- 2 356/401 (0 OR, 2 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/399 BY ALIGNMENT IN LATERAL DIRECTION
 356/401 .With registration indicia (e.g., scale)
- 2 356/614 (1 OR, 1 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/614 POSITION OR DISPLACEMENT
- 2 360/137 (2 OR, 0 XR)
 Class 360 : DYNAMIC MAGNETIC INFORMATION STORAGE OR
 RETRIEVAL
 360/137 MISCELLANEOUS
- 2 360/69 (0 OR, 2 XR)
 Class 360 : DYNAMIC MAGNETIC INFORMATION STORAGE OR
 RETRIEVAL
 360/69 AUTOMATIC CONTROL OF A RECORDER MECHANISM
- 2 360/74.1 (0 OR, 2 XR)
 Class 360 : DYNAMIC MAGNETIC INFORMATION STORAGE OR
 RETRIEVAL
 360/69 AUTOMATIC CONTROL OF A RECORDER MECHANISM
 360/71 .Controlling the record
 360/74.1 / ..Stopping or reversing
- 2 377/129 (0 OR, 2 XR)
 Class 377 : ELECTRICAL PULSE COUNTERS, PULSE DIVIDERS, OR
 SHIFT REGISTERS: CIRCUITS AND SYSTEMS
 377/129 PULSES CONTINUOUSLY CIRCULATED IN A CLOSED LOOP
- 2 377/72 (0 OR, 2 XR)
 Class 377 : ELECTRICAL PULSE COUNTERS, PULSE DIVIDERS, OR
 SHIFT REGISTERS: CIRCUITS AND SYSTEMS
 377/64 SHIFT REGISTER

10822193_CLSTITLES.txt

377/70	.Particular input circuit
377/72	..With feedback
2 399/16	(1 OR, 1 XR)
Class 399	: ELECTROPHOTOGRAPHY
399/9	DIAGNOSTICS
399/16	.Document handling
2 430/22	(0 OR, 2 XR)
Class 430	: RADIATION IMAGERY CHEMISTRY: PROCESS,
	COMPOSITION, OR PRODUCT THEREOF
430/22	REGISTRATION OR LAYOUT PROCESS OTHER THAN COLOR
	PROOFING
2 438/11	(1 OR, 1 XR)
Class 438	: SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/5	INCLUDING CONTROL RESPONSIVE TO SENSED
	CONDITION
438/10	.Electrical characteristic sensed
438/11	..Utilizing integral test element
2 438/622	(0 OR, 2 XR)
Class 438	: SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/584	COATING WITH ELECTRICALLY OR THERMALLY
	CONDUCTIVE MATERIAL
438/597	.To form ohmic contact to semiconductive
	material
438/618	..Contacting multiple semiconductive regions
	(i.e., interconnects)
438/622	...Multiple metal levels, separated by
	insulating layer (i.e., multiple level metallization)
2 700/121	(0 OR, 2 XR)
Class 700	: DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
	SPECIFIC APPLICATIONS
700/90	SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/95	.Product assembly or manufacturing
700/117	..Particular manufactured product or operation
700/121	...Integrated circuit production or
	semiconductor fabrication
2 714/725	(0 OR, 2 XR)
Class 714	: ERROR DETECTION/CORRECTION AND FAULT
	DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/725	..Programmable logic array (PLA) testing
2 716/4	(0 OR, 2 XR)
Class 716	: DATA PROCESSING: DESIGN AND ANALYSIS OF
	CIRCUIT OR SEMICONDUCTOR MASK
716/1	CIRCUIT DESIGN
716/4	.Testing or evaluating